Notice of References Cited Application/Control No. 10/522,036 Examiner Sin J. Lee Applicant(s)/Patent Under Reexamination MARUYAMA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,673,512	01-2004	Uenishi et al.	430/270.1
	В	US-			
	O	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	υ						
	V						
	w						
	х	-					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.